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	3175-Z	10/086,214
	APPLICANT	Laung-Terng Wang et al
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	February 27, 2002	2184

## U.S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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						YES NO

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	M. Abrumovici et al, <i>Digital-Systems-Testing-and-Testable-Design</i> , Computer Science Press, New York, 1990	/COPY UNAVAILABLE/
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